


<b>Search Notes</b>  	<b>Application/Control No.</b>  10825172	<b>Applicant(s)/Patent Under Reexamination</b>  MARTINEAU ET AL.
	<b>Examiner</b>  Tan, Alvin H	<b>Art Unit</b>  2173

SEARCHED			
Class	Subclass	Date	Examiner
715	734	6/11/07 (Updated 12/3/07)	AT (AT)

SEARCH NOTES		
Search Notes	Date	Examiner
715/733, 734, 737, 853, 854, 855 (text search only - see search history printout)	6/11/07	AT
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	6/11/07	AT
Above - UPDATED	12/3/07	AT
NPL (ACM Portal)	6/11/07	AT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner